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FACSIMILE COVER SHEET

December 19, 2006

Receiver: Examiner Lan Vinh
Group Art Unit 1765

FAX #: 571-273-8300

Sender: Chereyce R. Brown, Patent Assistant to:
Anna Gavrilova

Our Ref. No.: NOVLP068/NVLS-2818
Application No.: 10/690,084

Re: Response D

Pages Including Cover Sheet(s): 10

MESSAGE:

Please see the attached documents.

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Koos et al.

Attorney Docket No.:
NOVLP068/NVLS-2818

Application No.: 10/690,084

Examiner: Vinh, Lan

Filed: October 20, 2003

Group: 1765

Title: METHOD FOR FABRICATION OF
SEMICONDUCTOR INTERCONNECT
STRUCTURE WITH REDUCED
CAPACITANCE, LEAKAGE CURRENT, AND
IMPROVED BREAKDOWN VOLTAGE

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence is being transmitted by
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Signed: 

Cherey R. Brown

RESPONSE D

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

This is in response to the non-final Office Action mailed November 30, 2006.

Listing of claims begins on page 2 of this paper.

Remarks begin on page 9 of this paper.